



University
of Glasgow



Performance studies of Low Gain Avalanche Detectors coupled to the Timepix3 ASIC

Dima Maneuski, University of Glasgow
Jerome Alozy, CERN
Richard Bates, University of Glasgow
Mark Bullough, Micron Semiconductor Ltd
Lars Eklund, University of Uppsala
Lojius Lombigit, University of Glasgow
Neil Moffat, CNM Barcelona
Nicola Tartoni, Diamond Light Source
Mark Williams, University of Edinburgh

International Workshop
23rd iWoRiD
on Radiation Imaging Detectors

iWoRiD 2022

**23rd International Workshop on
Radiation Imaging Detectors**

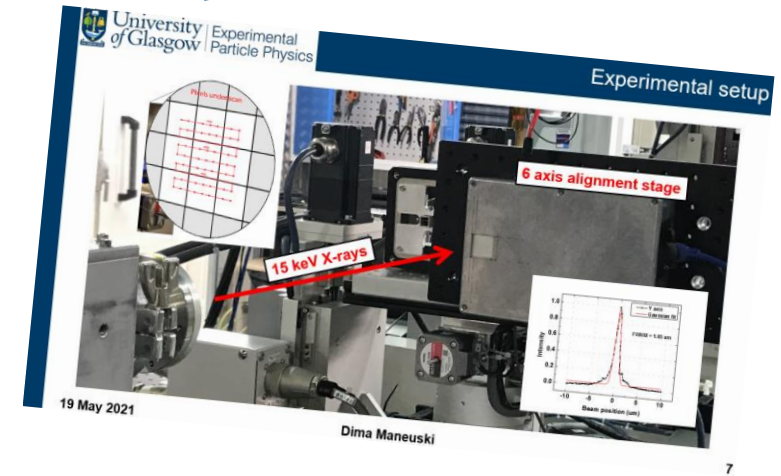
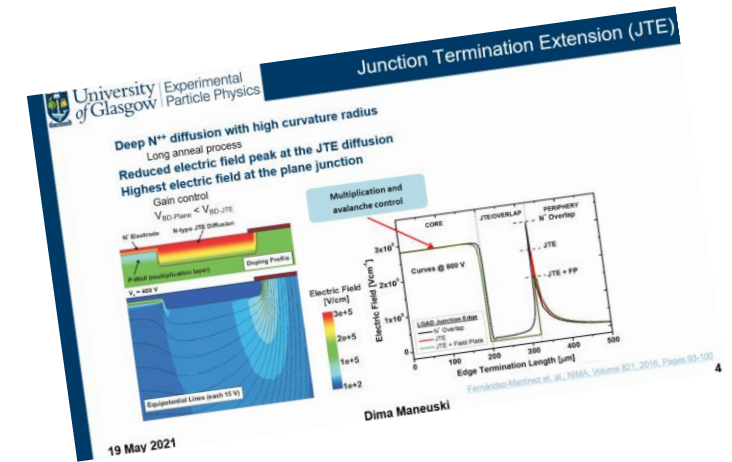
26 – 30 June 2022

Riva del Garda, Italy

<https://indico.cern.ch/event/1120714>

Table of contents

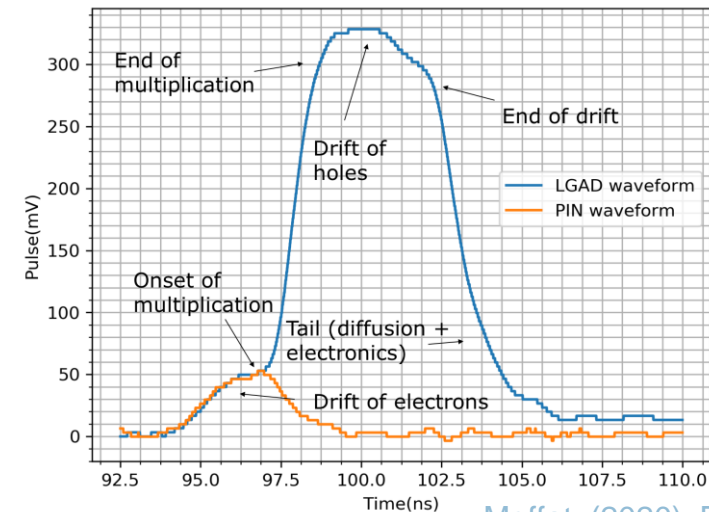
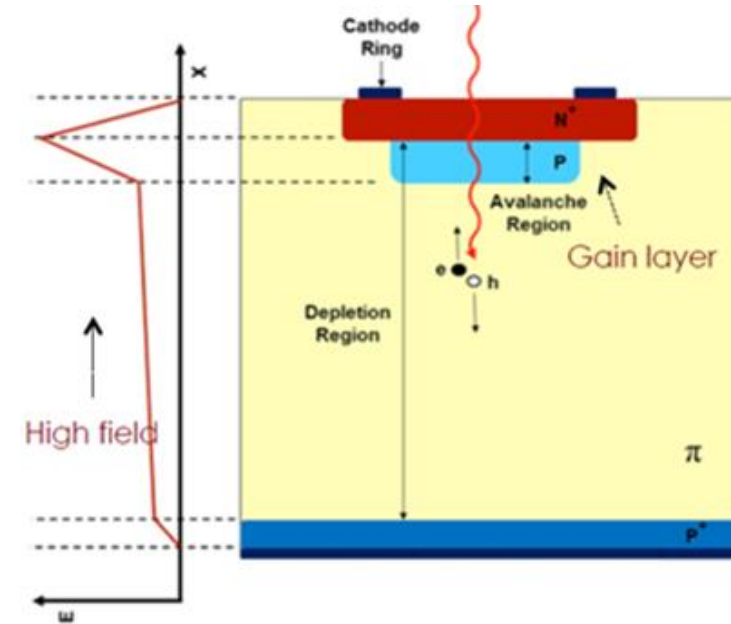
- Low Gain Avalanche Diodes (LGADs)
 - Research agenda and motivation
- Experiments at Diamond Light Source
 - Experimental setup
 - Devices under test
 - Results and discussion
- Future work
- Conclusions



Research agenda and motivation

- Fast timing silicon pixel detectors (sub 100 ps)
- “Tender” energy x-rays detectors (and below)
- Understand LGAD technology
- Create simulation models
- Develop fabrication process
- Build characterisation infrastructure
- Explore potential applications
- Synchrotron applications
- LHCb VELO upgrade

LGAD principle



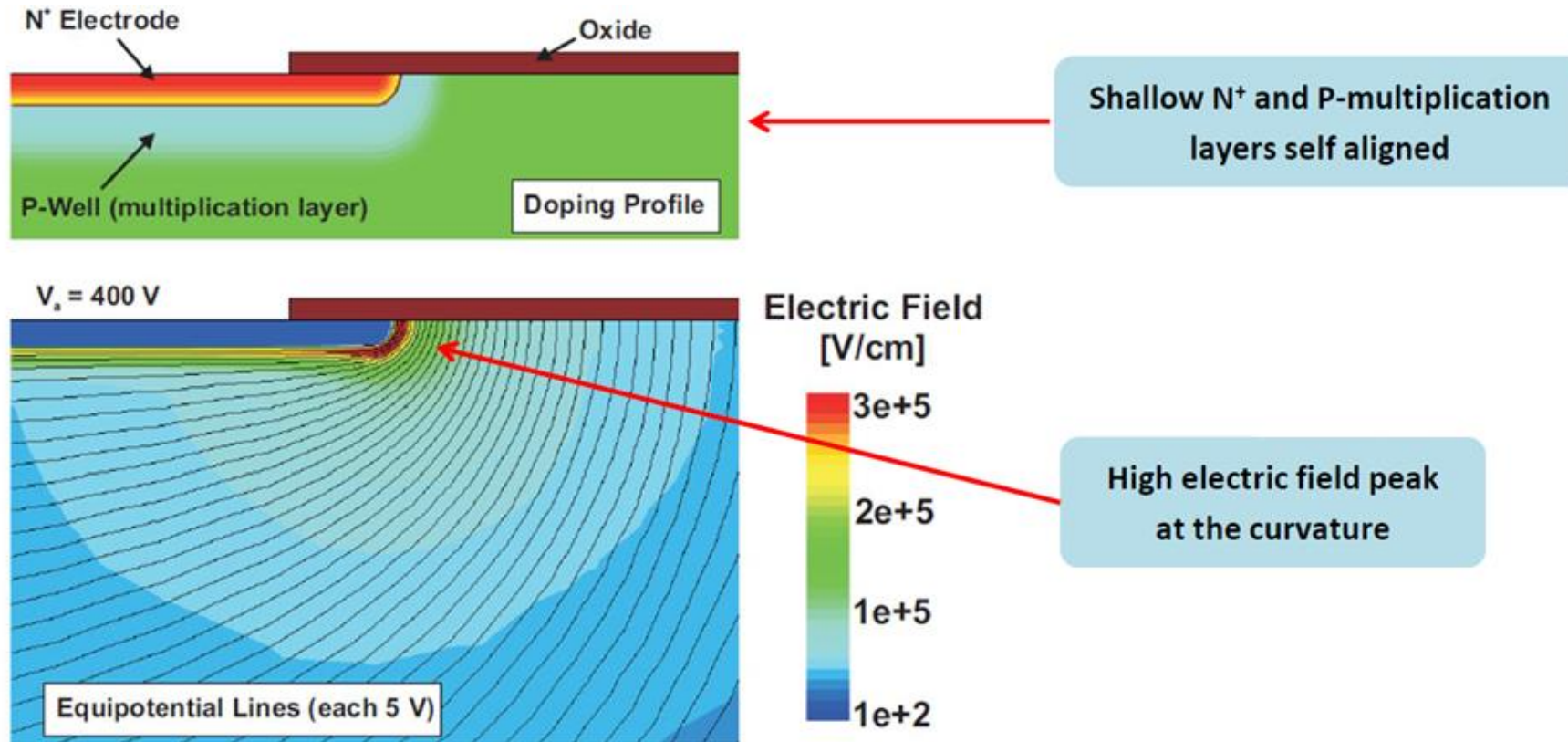
[Moffat, \(2020\), PhD thesis](#)

The electric field at the corner curved section of the N^+/P^+ junction is much higher than that of the flat junction region

where Gain is required

Avalanche at the N^+/P^+ curvature at a very low reverse voltage

-> premature breakdown



Deep N⁺⁺ diffusion with high curvature radius

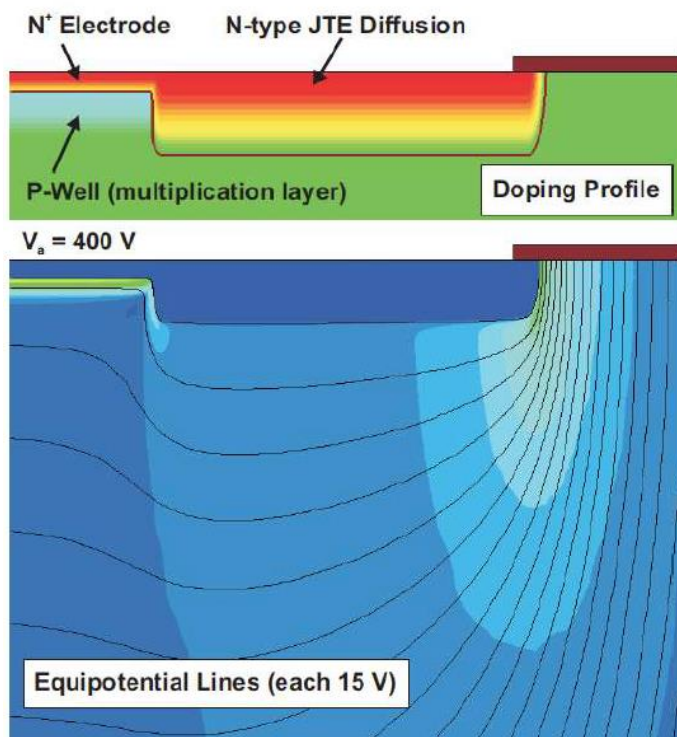
Long anneal process

Reduced electric field peak at the JTE diffusion

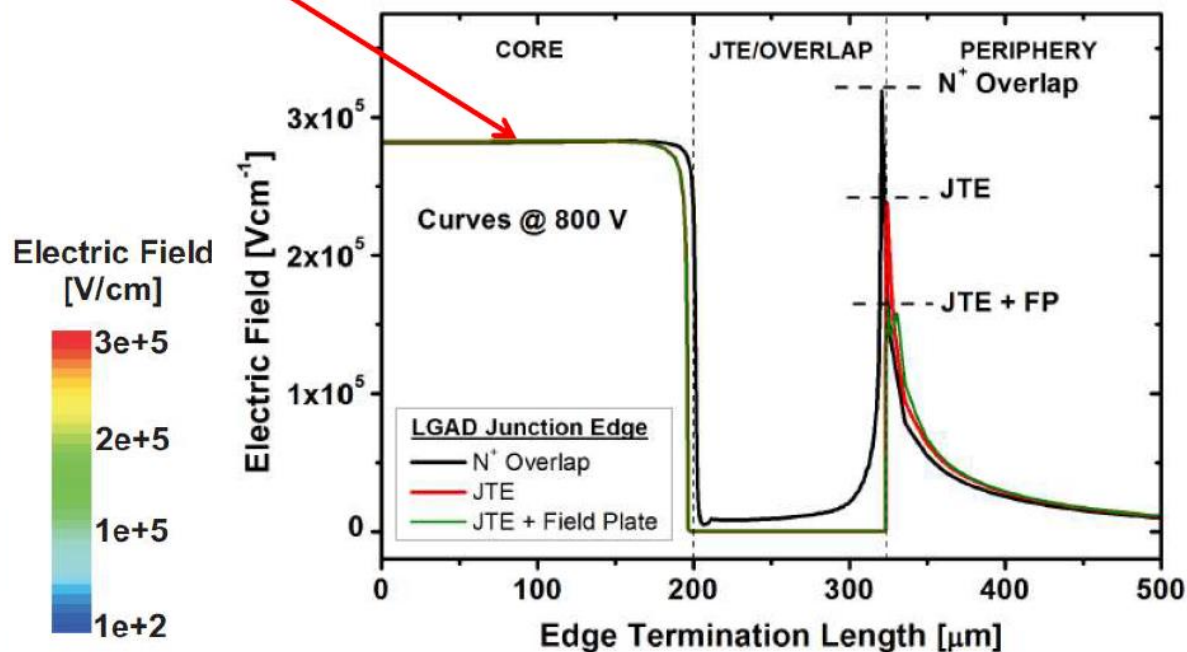
Highest electric field at the plane junction

Gain control

$$V_{BD-Plane} < V_{BD-JTE}$$



Multiplication and avalanche control

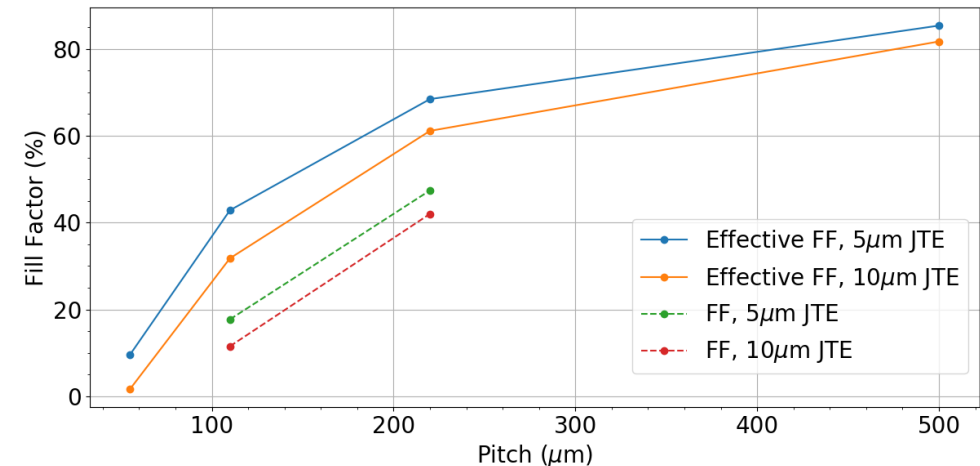
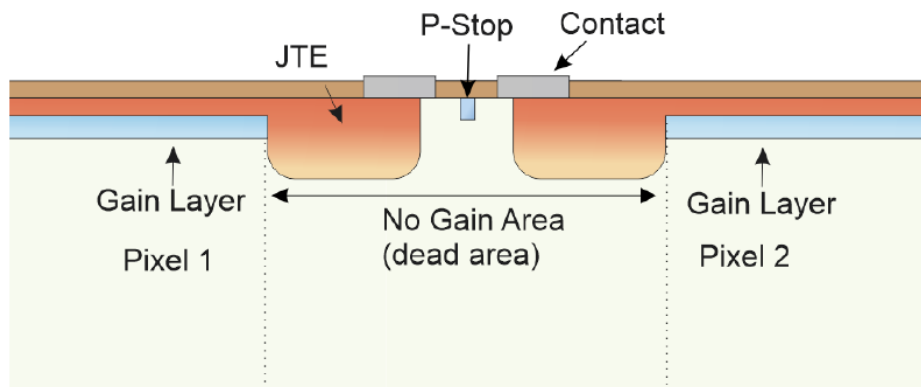


Geometric fill factor

$$\text{Fill Factor} = \frac{\text{Gain Area}}{\text{Total Area}}$$

Caused by JTE around each pixel

Need to take into account diffusion on JTE



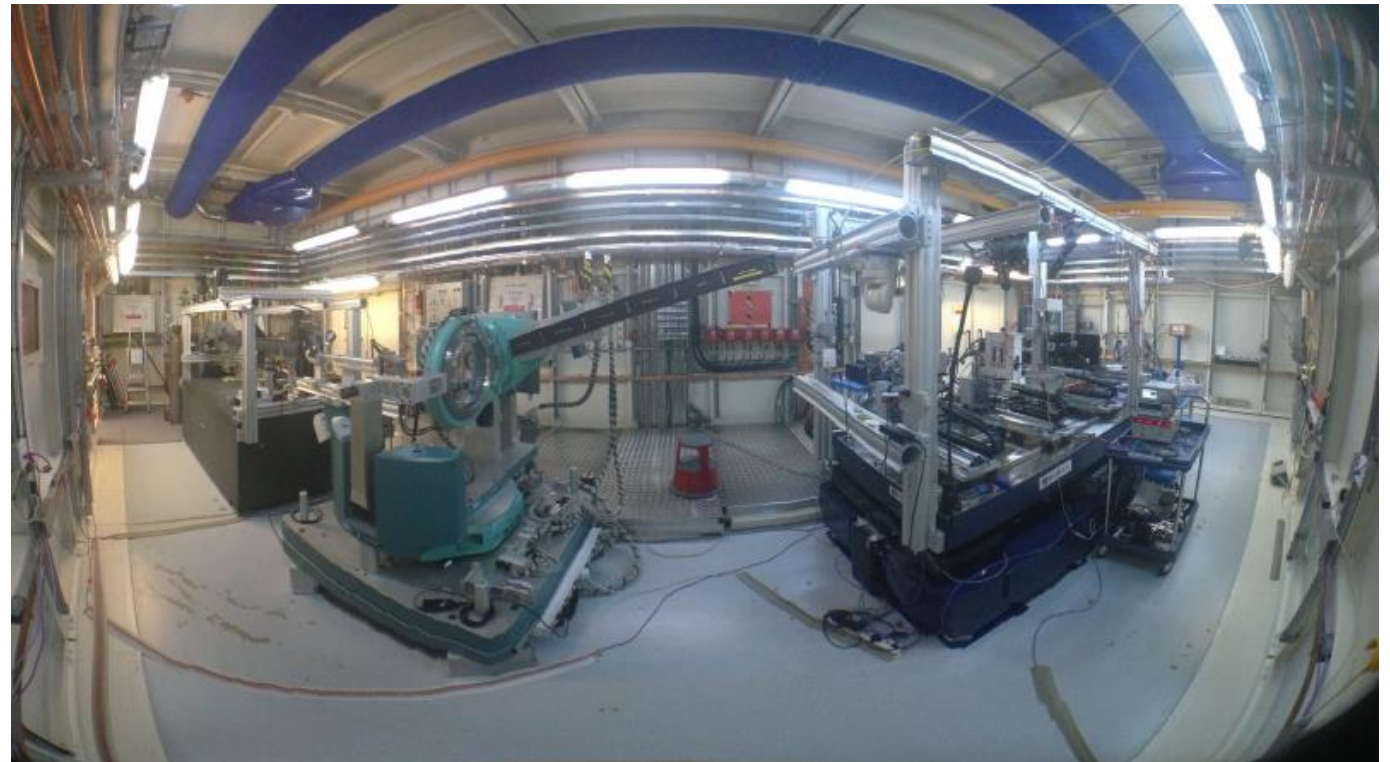
50 x 50 μm² pixel – JTE 10 μm -> fill factor < 10%

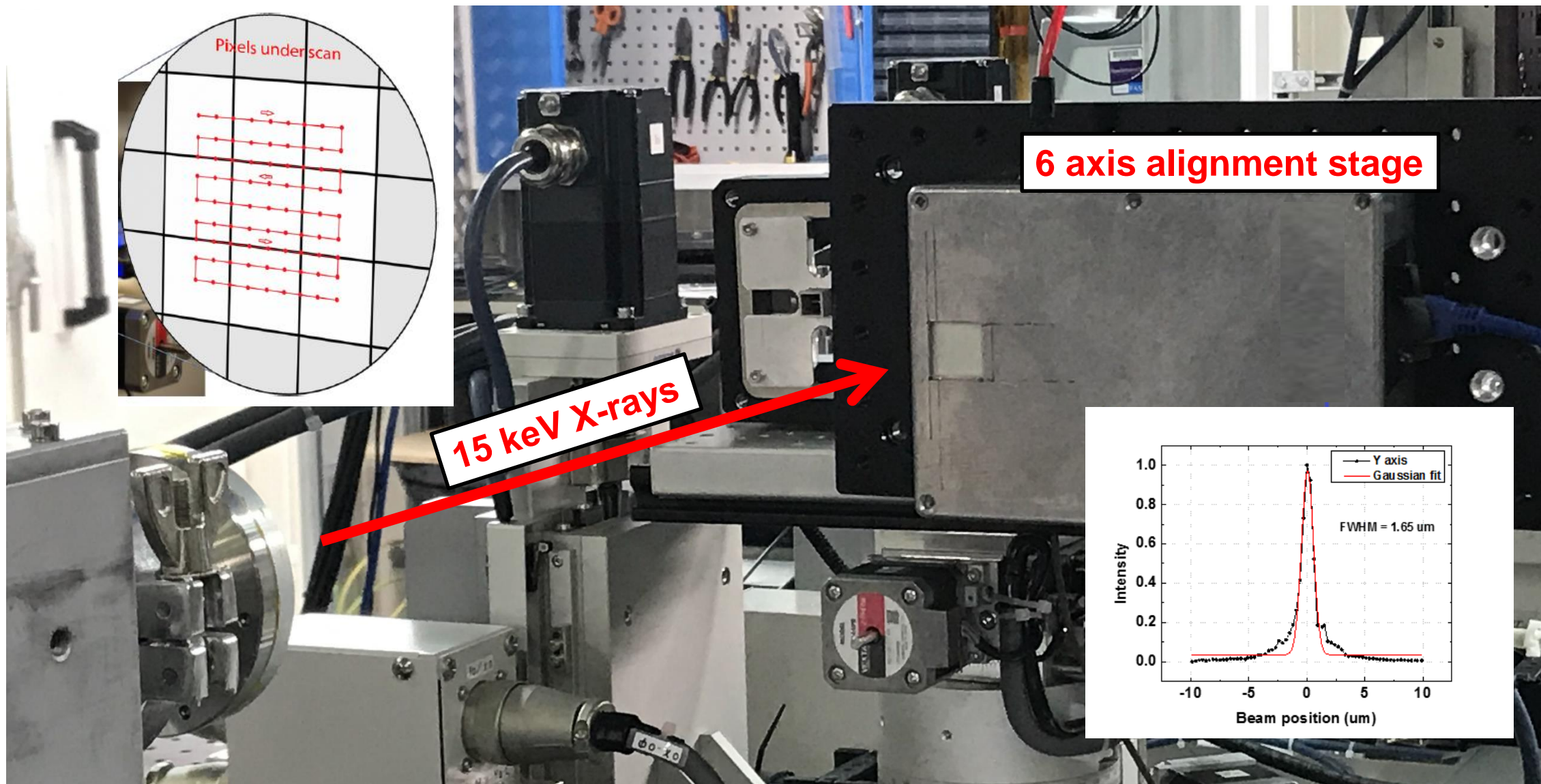
B16: Test Beamline

- Flexible and versatile beamline for testing new developments in optics and detector technology and for trialling new experimental techniques
- 4 – 45 keV photon energy range
- Operational modes:
 - Focused, unfocused
 - Monochromatic, white beam
 - High flux

What we use

- 15 keV monochromatic beam
- Focused to about a micron FWHM





Devices produced and tested

- C04 - 110 um pixel, 10 um JTE
- C06 - 110 um pixel, 20 um JTE
- D04 - 55 um pixel, 5 um JTE

- Each device has control no-multiplication region of 9x9 pixels in the right bottom corner

- I will show 110 um, 10 um JTE in detail
- I will show 110 um, 20 um JTE as comparison to 10 um JTE
- I will show 55 um, 5 um JTE

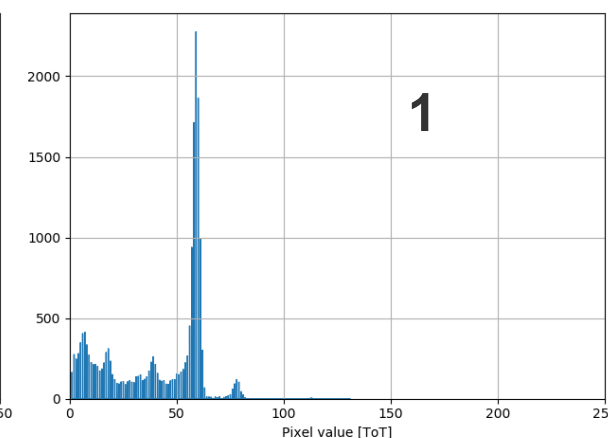
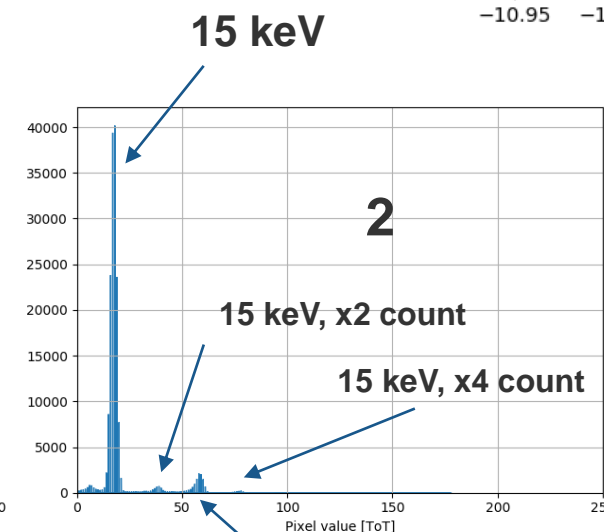
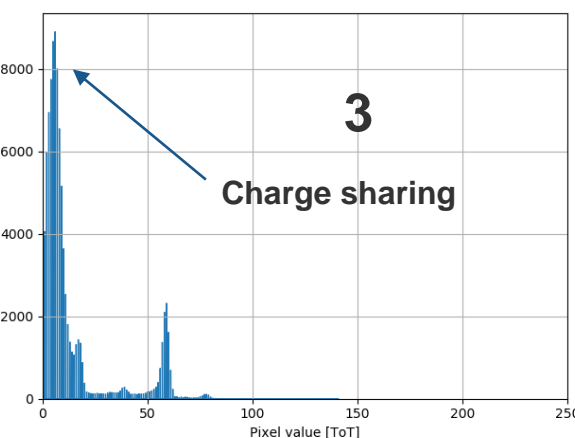
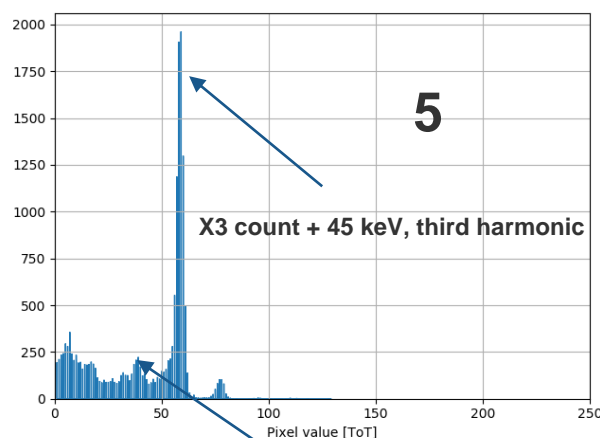
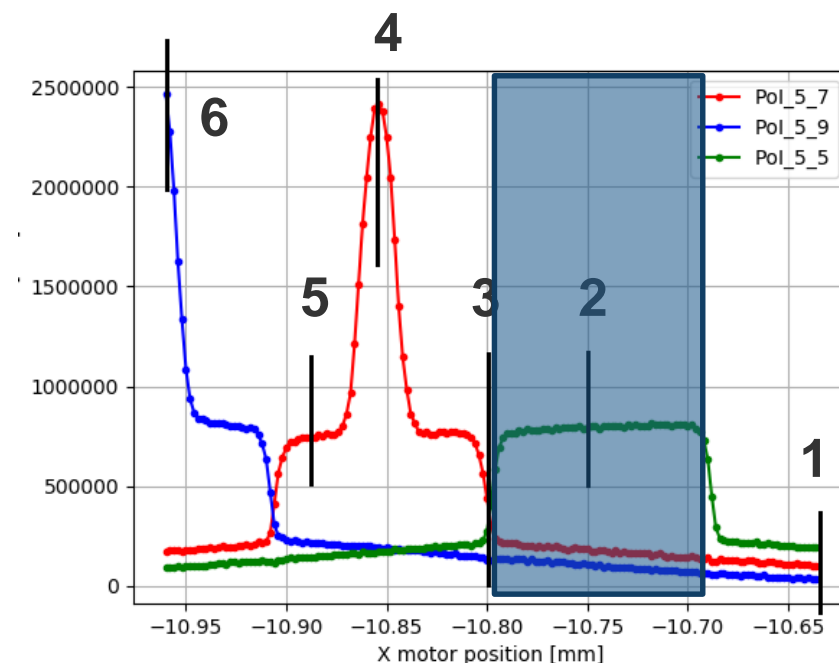
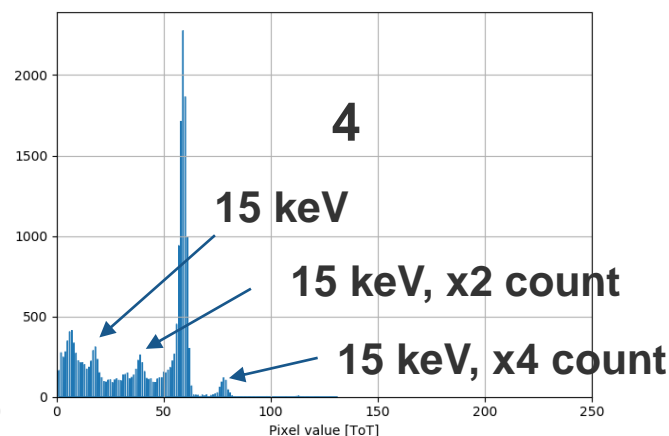
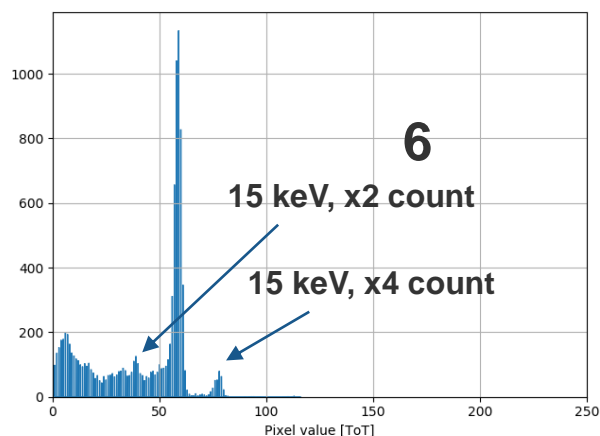
Tests performed

- Line scan over Pixel of Interest (PoI) @ V
- Voltage scan in the middle of PoI
- 2D scan @ V_{max}

TPX3 settings

- ToT+ToA mode, data-driven
- AdvaDAQ TPX3 USB3.0

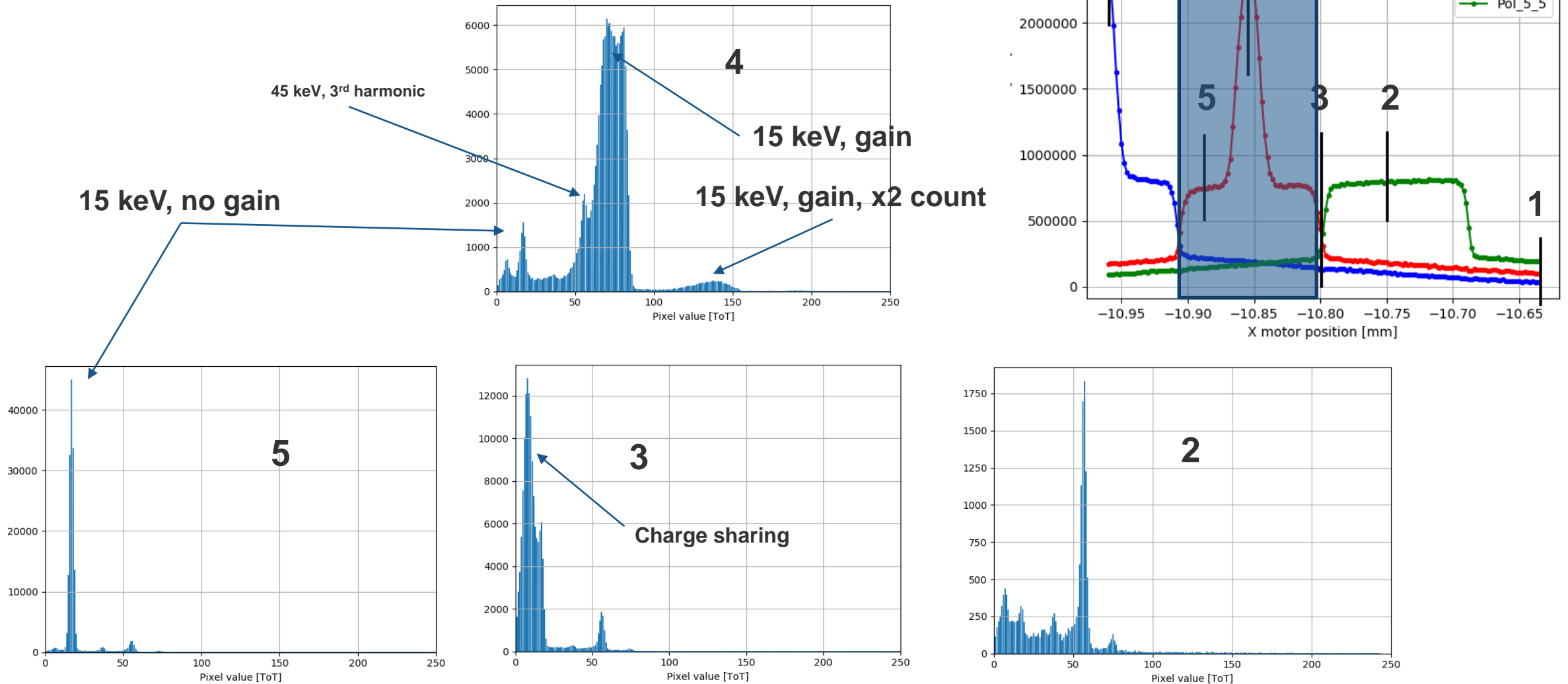
1D line scan, no gain pixel (5, 5), -350V



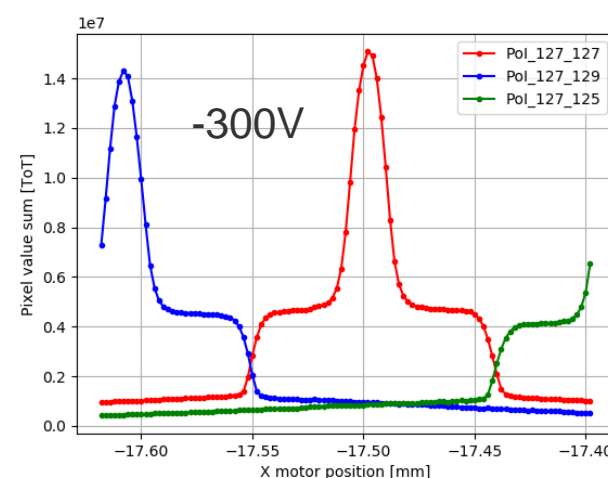
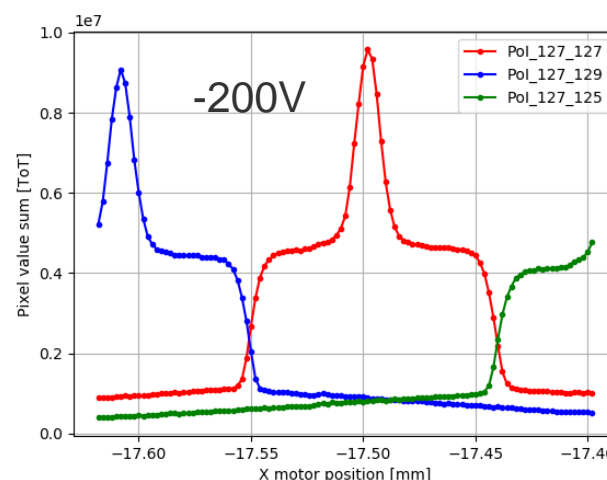
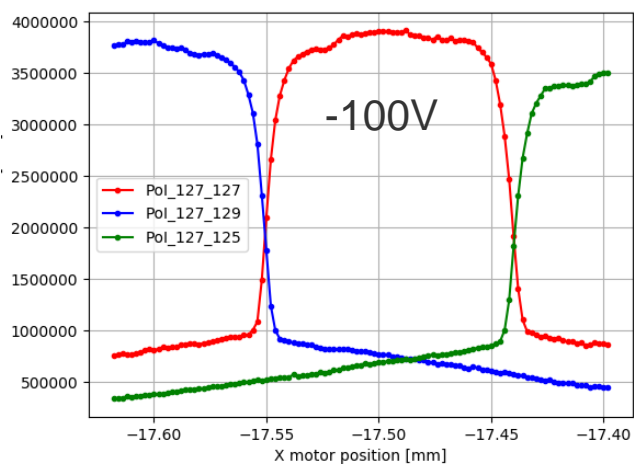
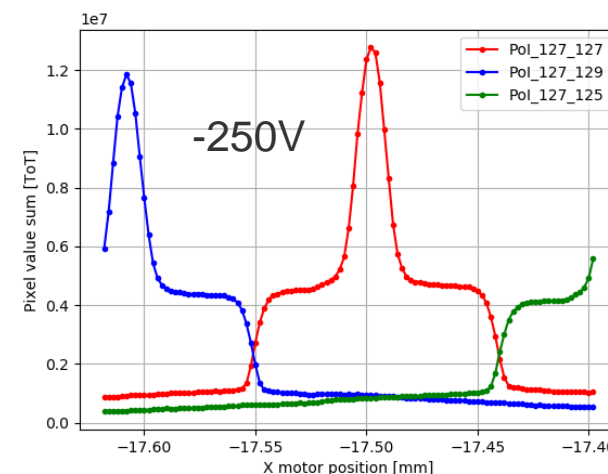
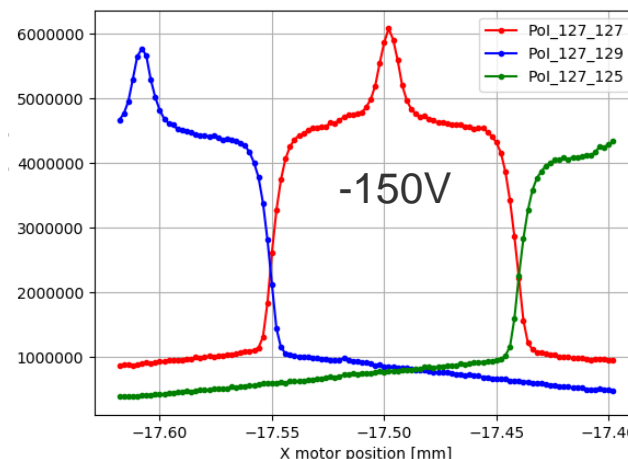
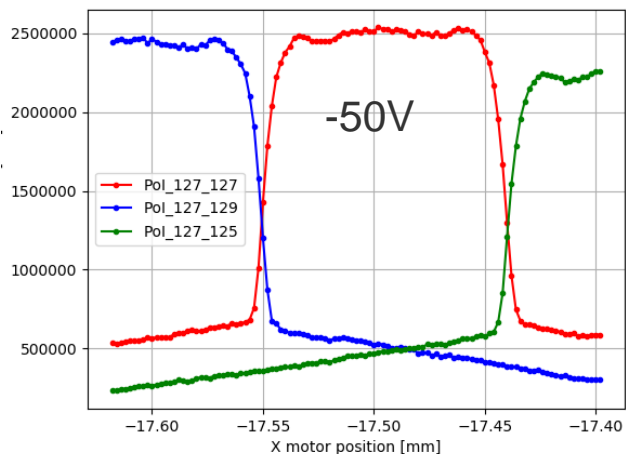
15 keV, x2 count

15 keV, x3 count + 45 keV (3rd harmonic)

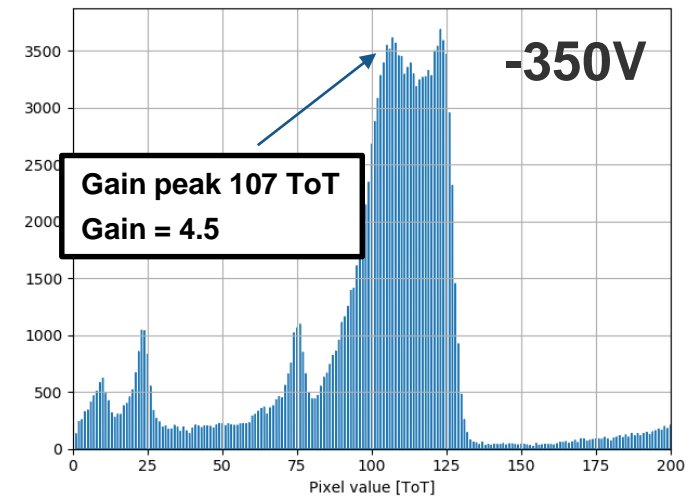
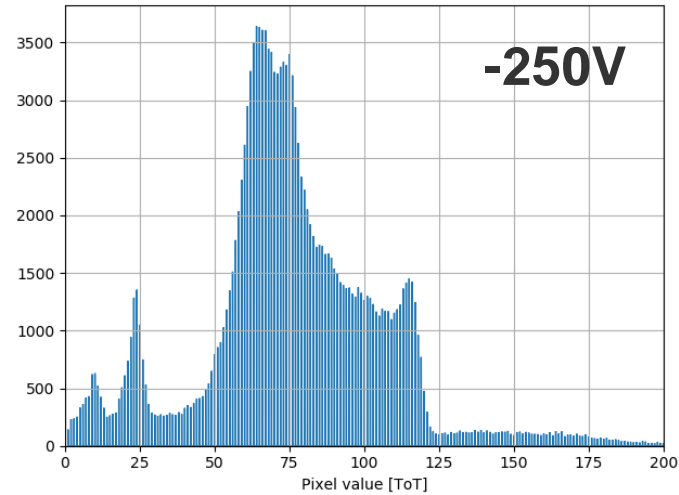
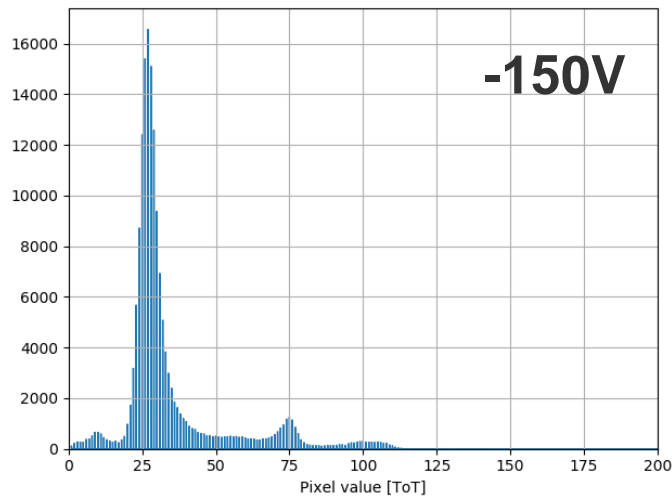
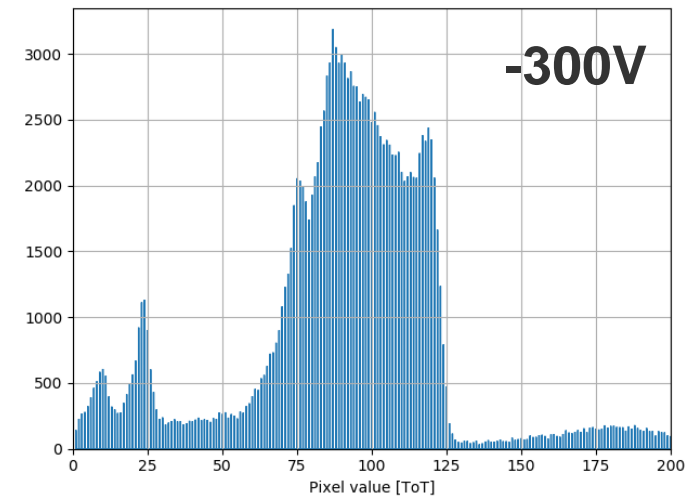
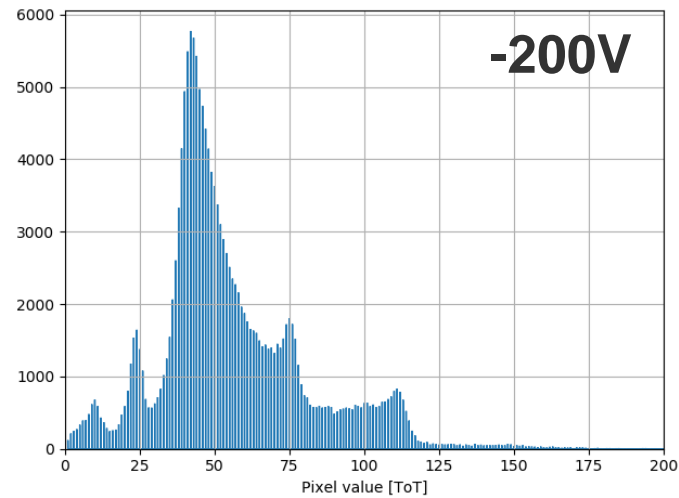
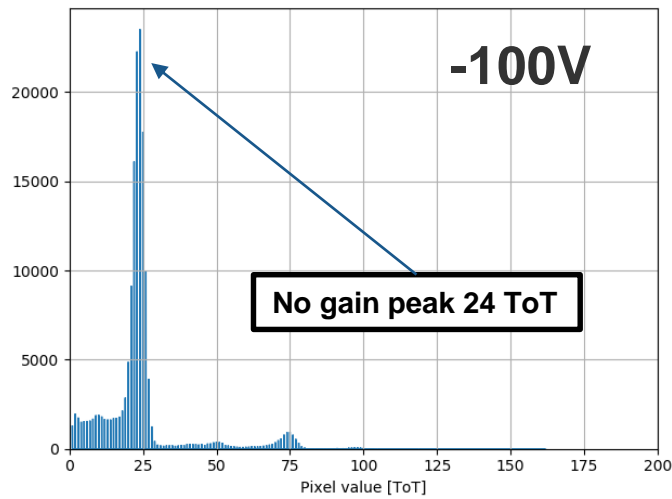
1D line scan, gain pixel (5, 7), -350V



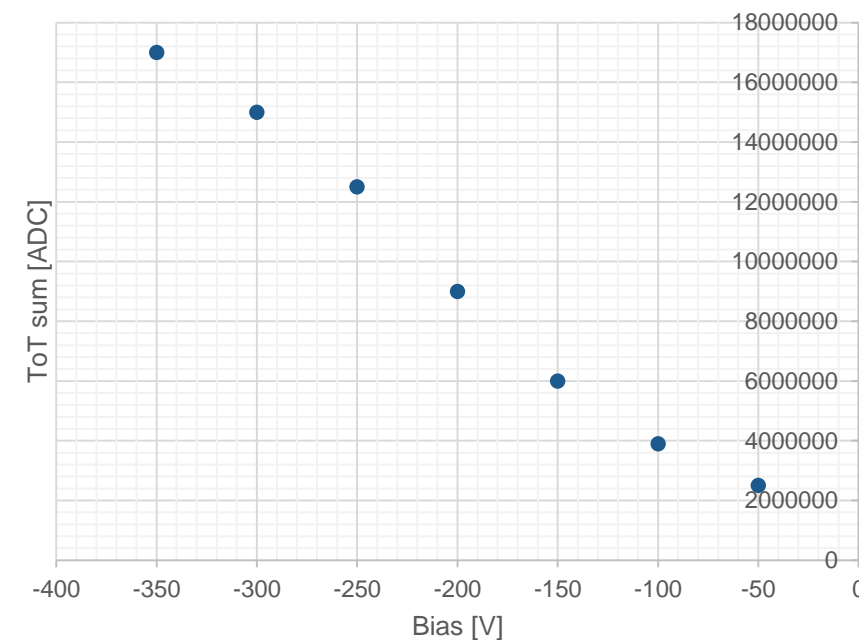
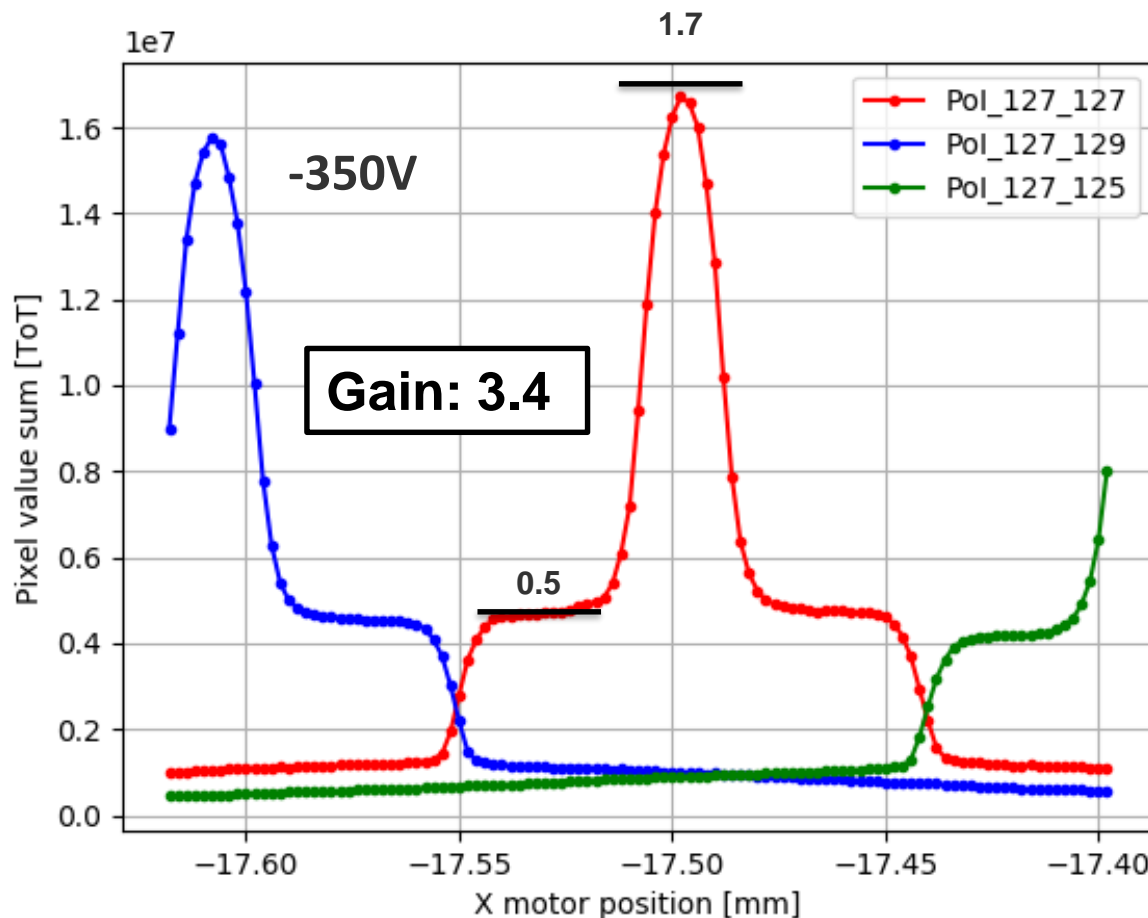
1D line scans @ voltages, gain pixel (127, 127)



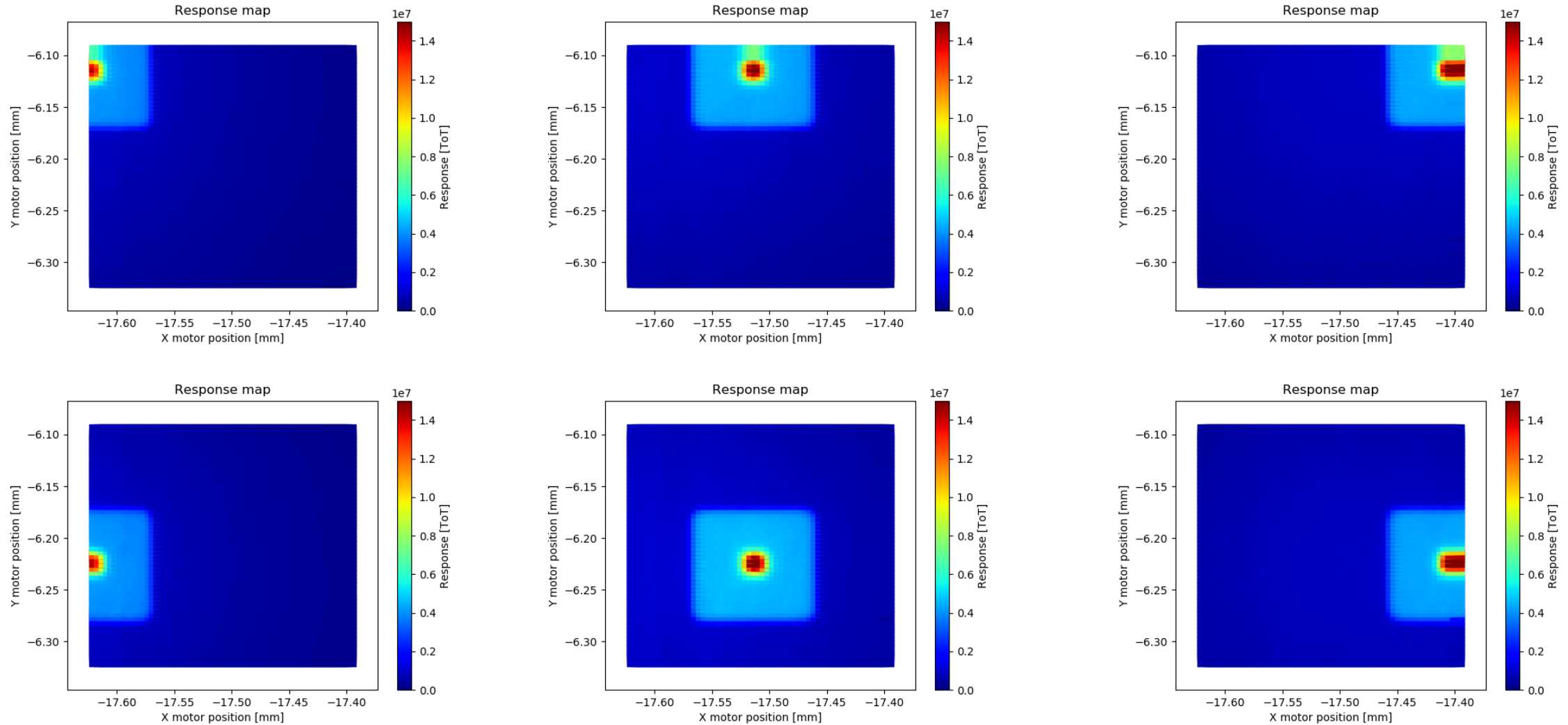
Spectrum in the middle of gain pixel (127, 127)



Gain @ voltages, gain pixel (127, 127)



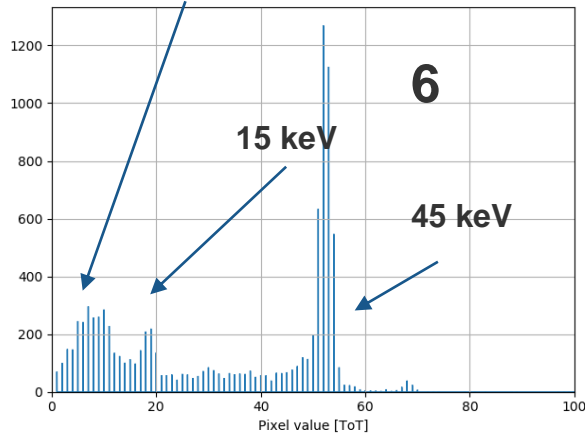
2D scan (-350V)



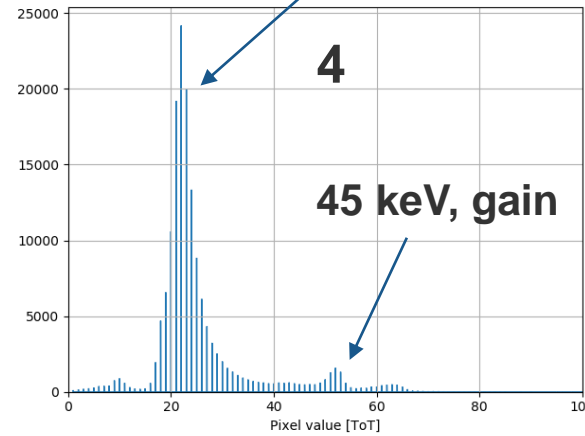
1D line scan, gain pixel (5, 7), -350V

Note! No x2 count peak, so 45 keV is 3rd harmonic only!

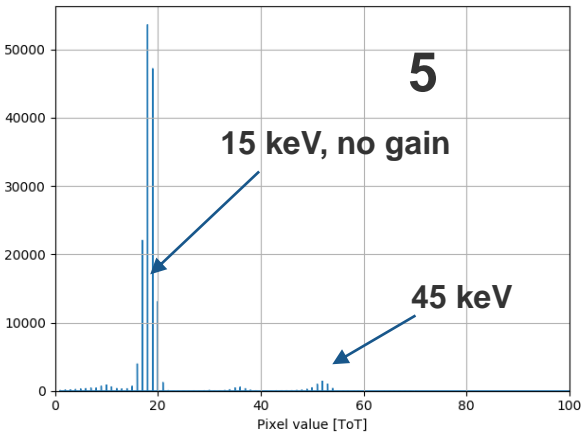
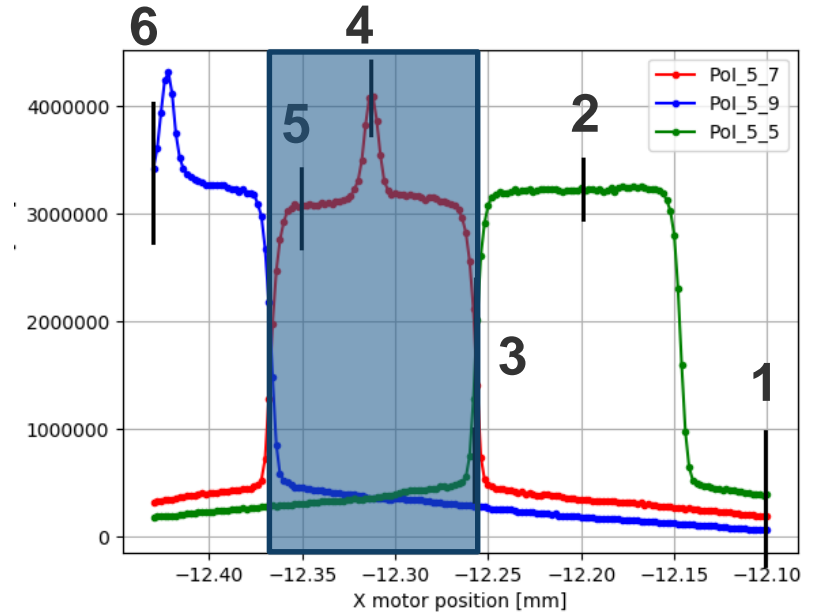
Charge sharing



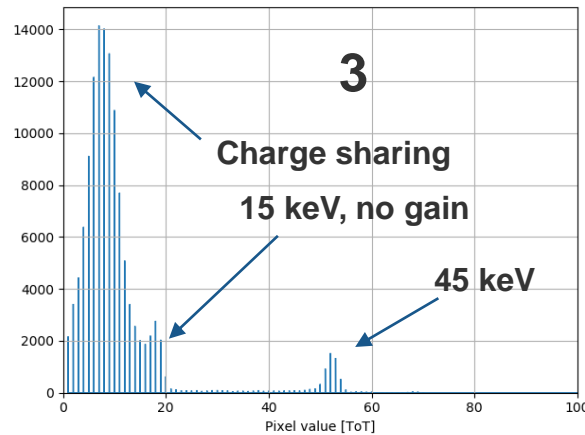
15 keV, gain



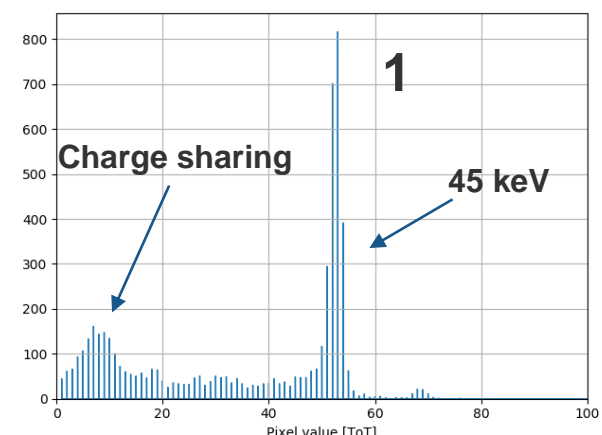
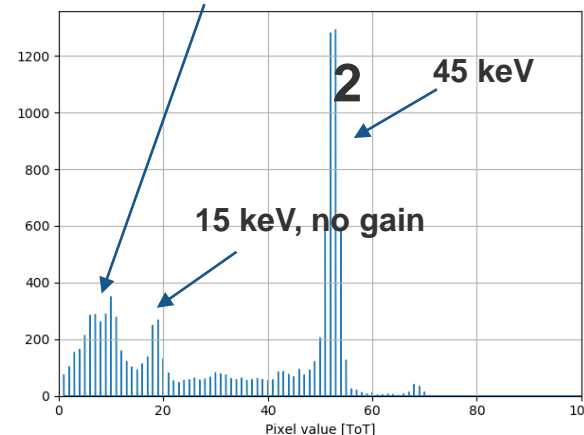
45 keV, gain



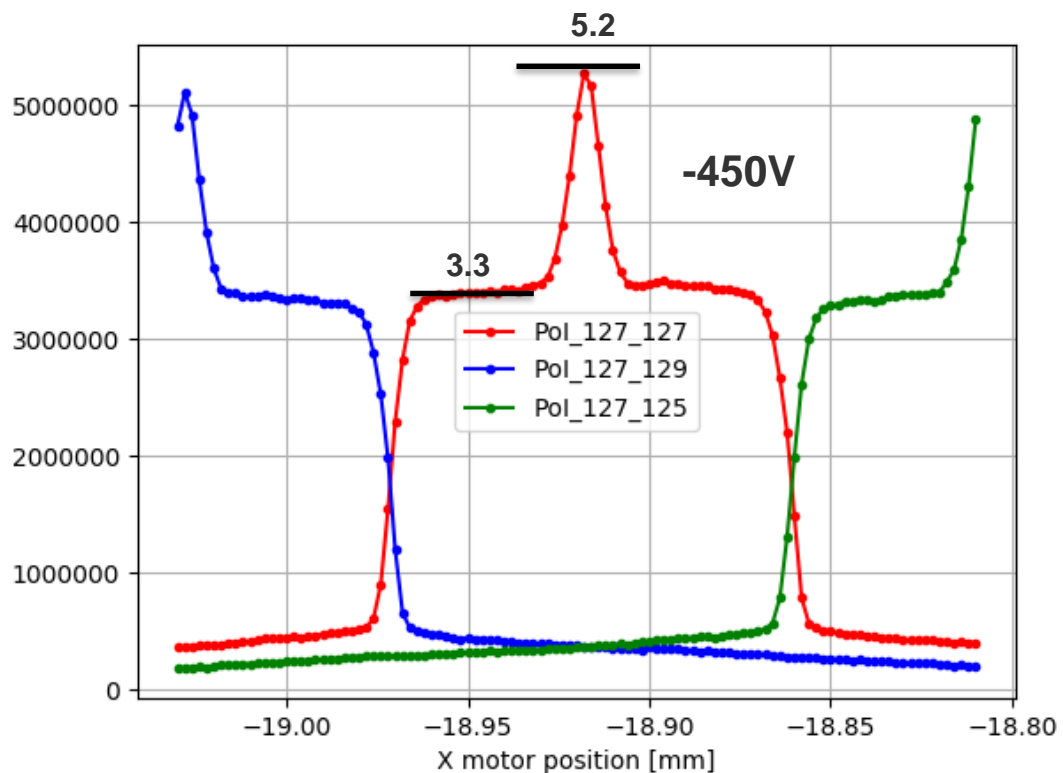
3



Charge sharing

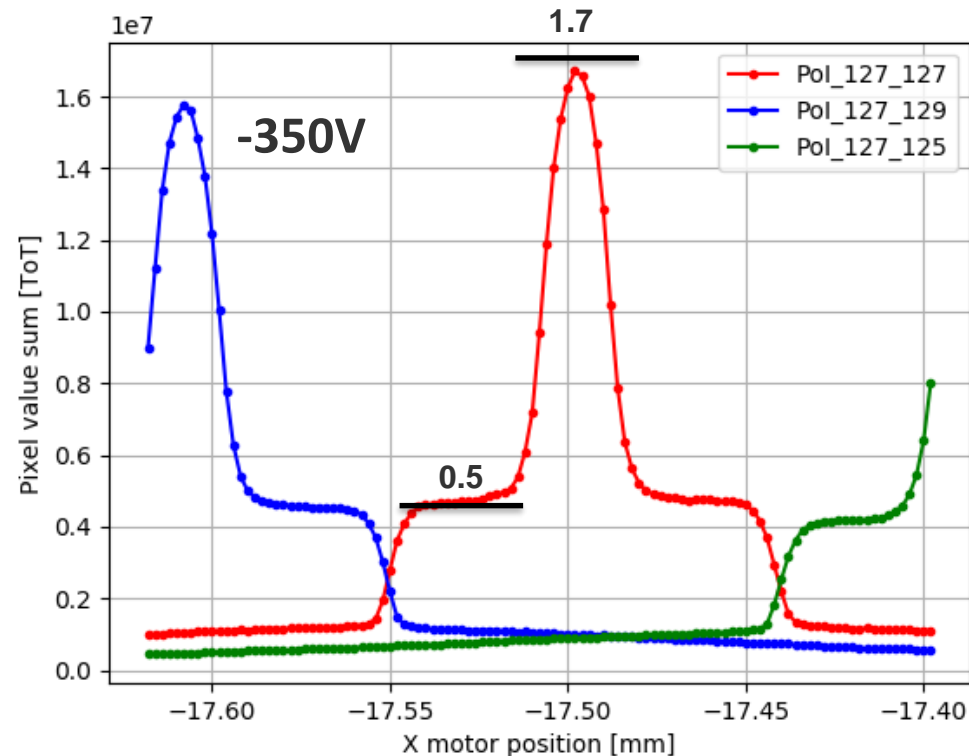


110 um pixel, 20 um JTE



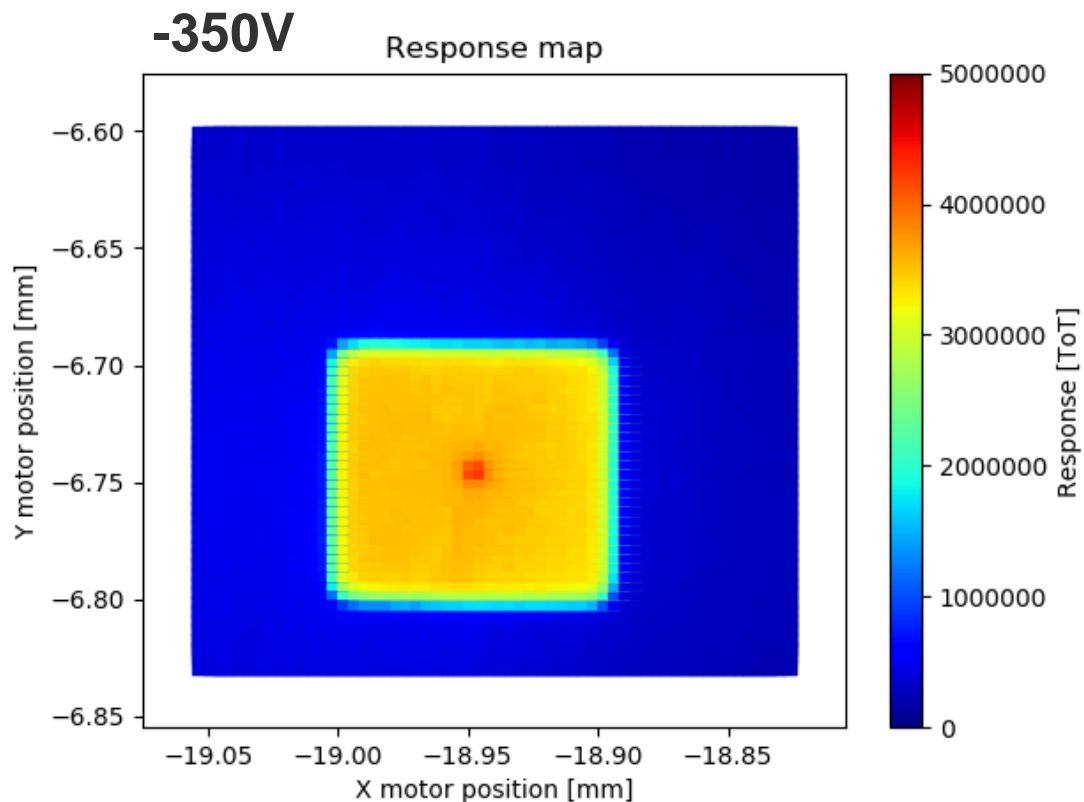
Gain: 1.6

110 um pixel, 10 um JTE

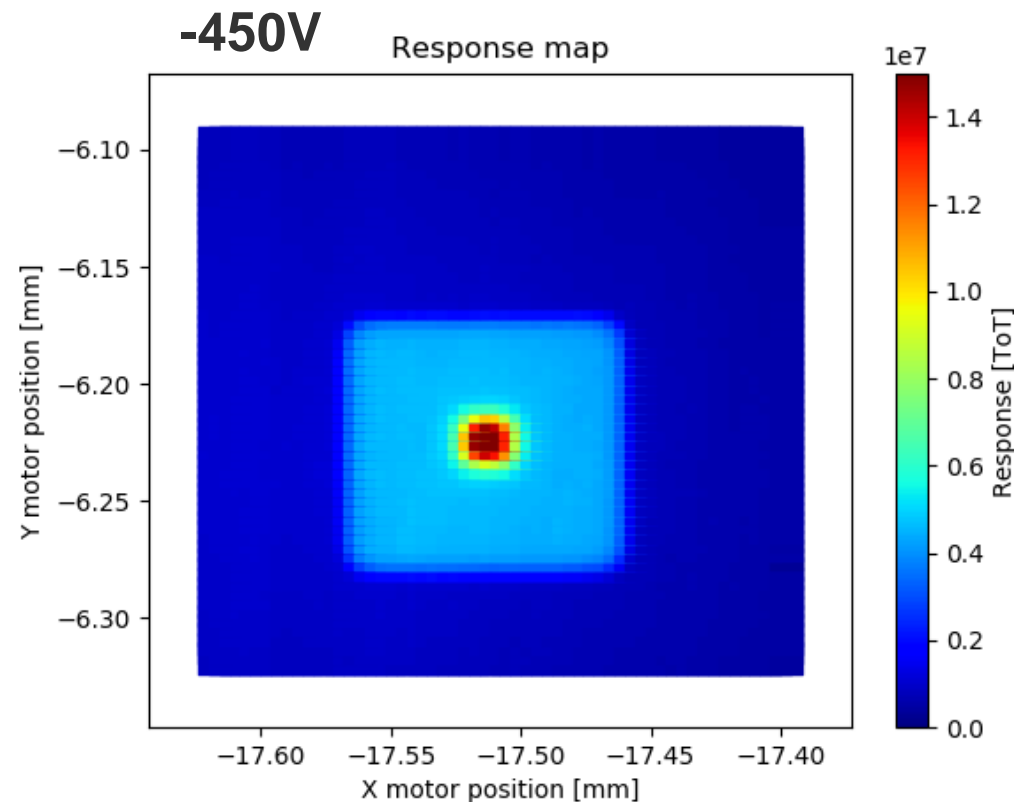


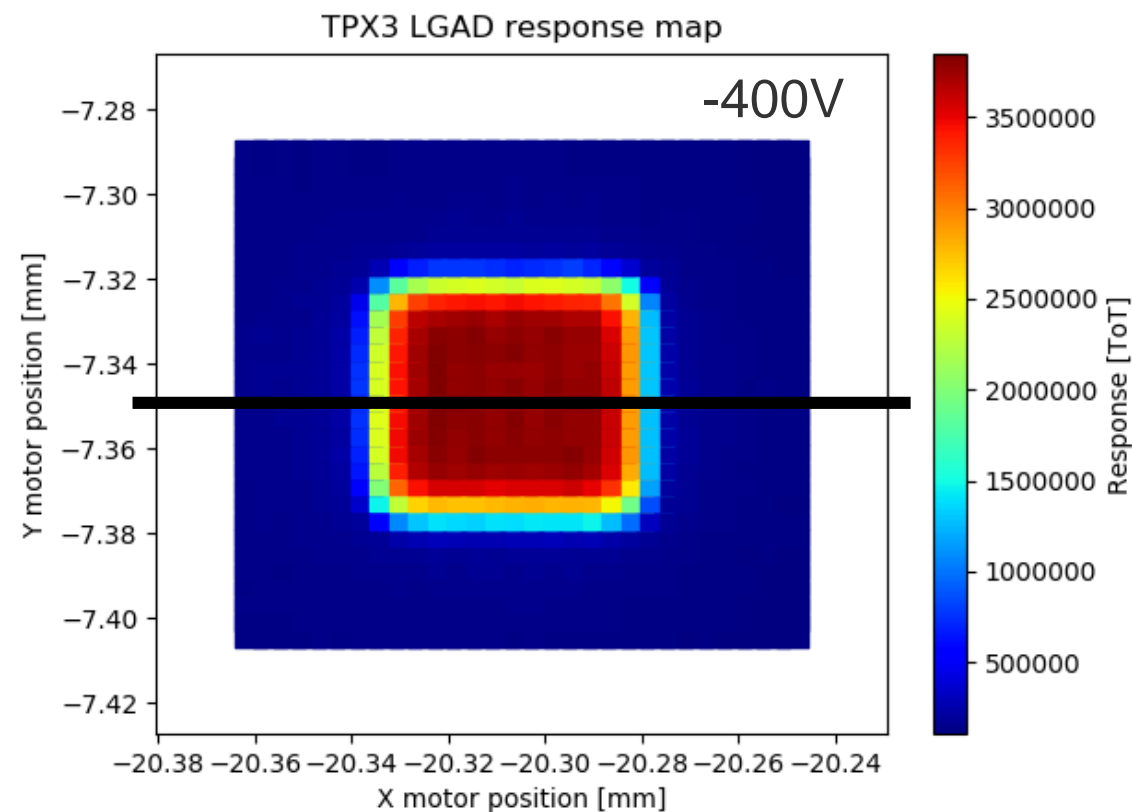
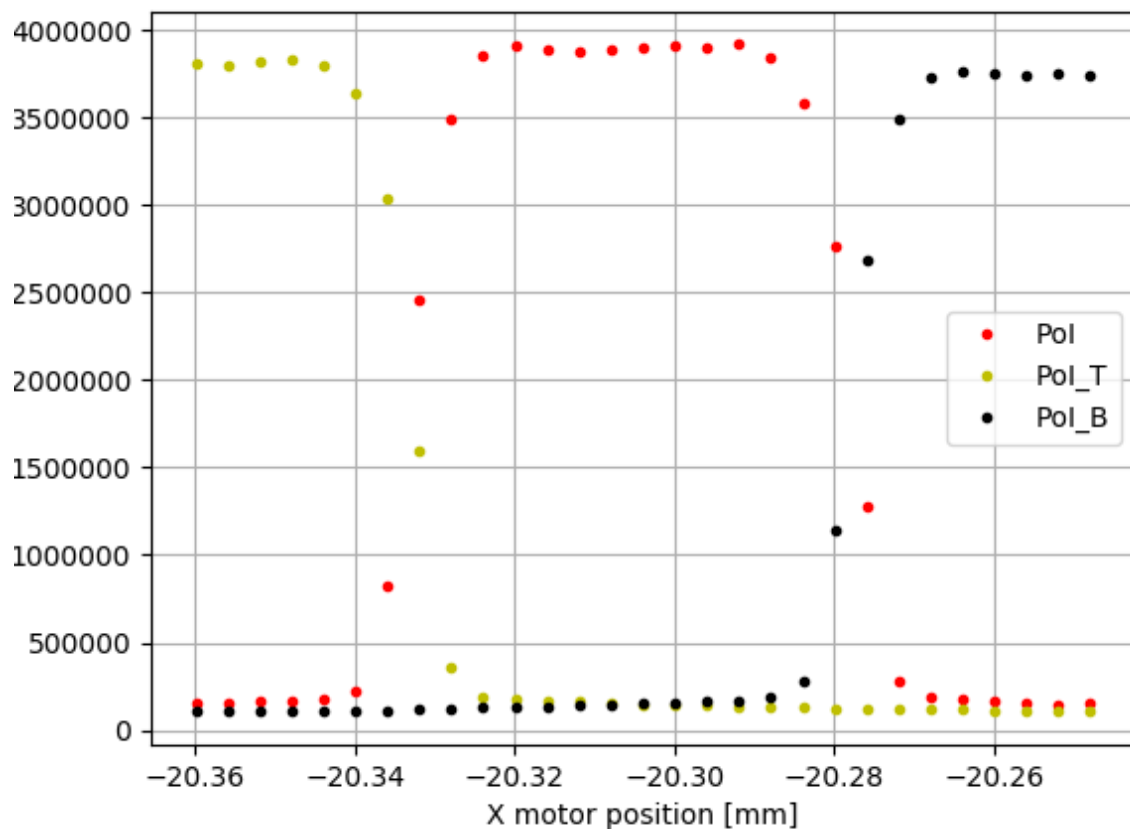
Gain: 3.4

110 μm pixel, 20 μm JTE



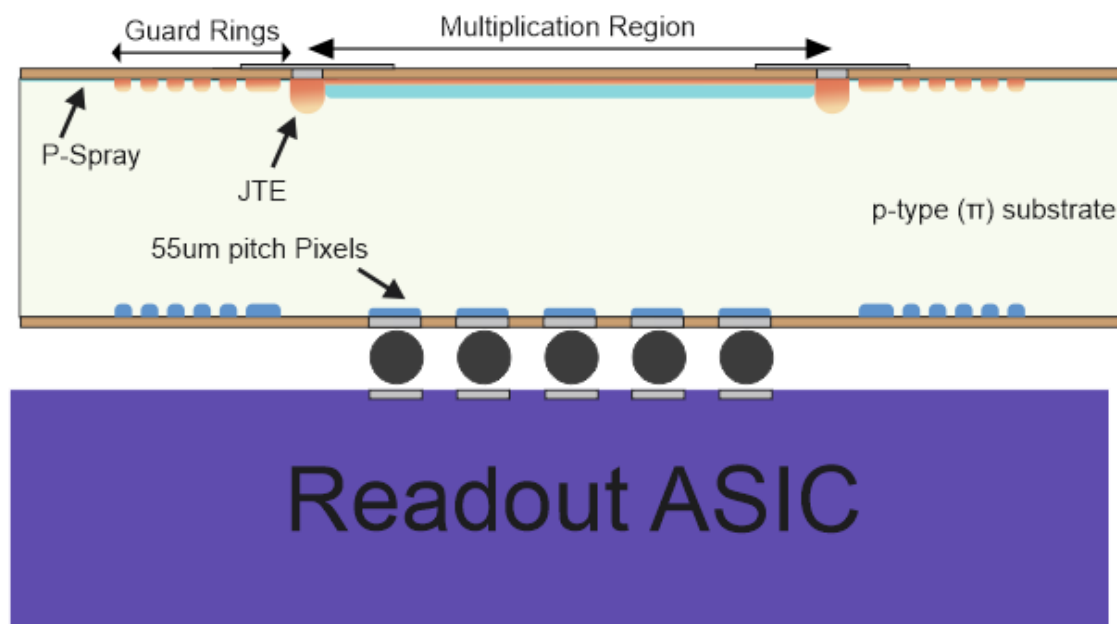
110 μm pixel, 10 μm JTE





No gain observed as expected

- Segmentation at the **ohmic contact**: strip and pixels.
- **Multiplication** extended over all the **device**.
- **P-type collector ring** at the ohmic side to extract leakage current.
- **JTE** to protect the n+/p curvature and **channel stopper** to avoid the depletion reaches the end of the detector.
- Readout is made by the strips/pixels: holes collection.

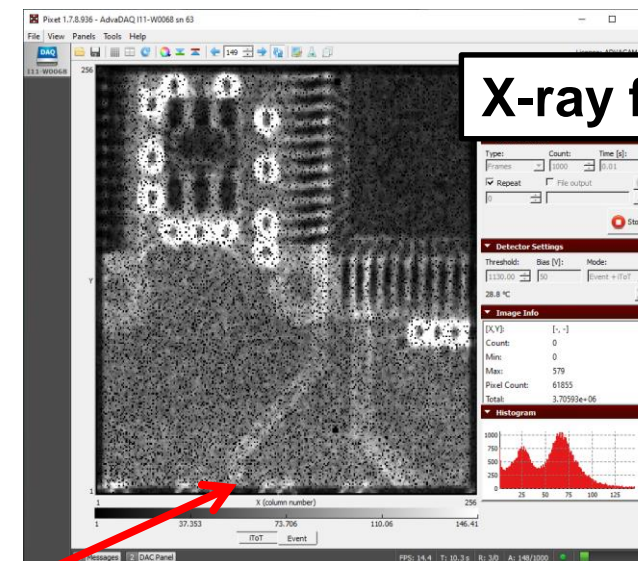


Cons

- Double side processing
- Backside sensitive to scratches
- Needs to be fully depleted

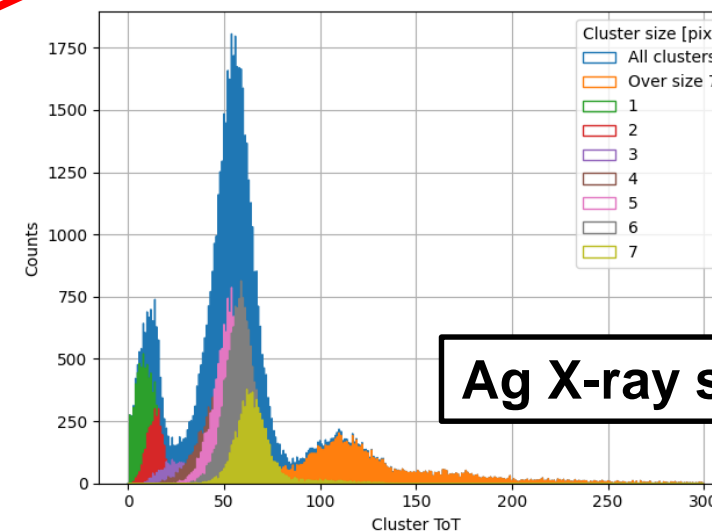
Status

- Wafers with two gain implants
- Pixels 55, 110, 220 μm
- Program to:
- Measure and understand spectra
- In-pixel gain uniformity:
 - Test beam at Diamond (Mid July)
 - Test beam at CERN SPS (Mid August)



X-ray flat field

3 pixel no gain rim around the detector



Ag X-ray source

Summary

- Strong program to design, produce and test LGAD devices
 - TCAD simulations
 - Mask design, device fabrication
 - Device characterisation by means of IV, CV, TCT and X-rays
- Predicted and demonstrated gain in small pixel devices
 - Various pixel sizes
 - Various JTE sizes
- Pathway to overcome existing limitations
 - Inverse LGAD design (fabricated, characterisation just started)
 - Trench isolation design (work in progress)

